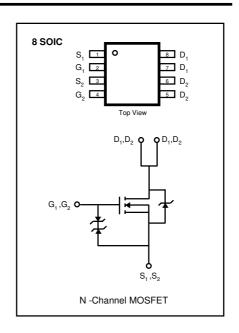
FEATURES

- $\ \ \, \Box \ \ \, \text{Lower} \, \, \mathsf{R}_{\mathsf{DS}(\mathsf{ON})}$
- Improved Inductive Ruggedness
- ☐ Fast Switching Times
- ☐ Low Input Capacitance
- Extended Safe Operating Area
- ☐ Improved High Temperature Reliability

Product Summary

Part Number	BV _{DSS}	R _{DS(on)}	I _D	
SSD2009	50V	0.13Ω	3.0A	



Absolute Maximum Ratings

Symbol	Characteristic	Value	Units		
V_{DSS}	Drain-to-Source Voltage	50	V		
	Continuous Drain Current T _A =25°C	3.0	Α		
I _D	Continuous Drain Current T _A =70°C	2.3	A		
I _{DM}	Drain Current-Pulsed ①	10.0	Α		
V_{GS}	Gate-to-Source Voltage	±20	V		
	Total Power Dissipation ($T_A=25^{\circ}C$)	2.0			
P_{D}	(T _A =70 °C)	1.3	W		
T _J , T _{STG}	Operating and Junction Storage	FF to .1F0	J		
7 / SIG	Temperature Range	- 55 to +150	C		

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
R_{\ThetaJA}	Junction-to-Ambient		62.5	°C/W



Electrical Characteristics (T_C =25 $^{\circ}$ C unless otherwise specified)

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
BV _{DSS}	Drain-Source Breakdown Voltage			1	٧	V _{GS} =0V,I _D =250μA
$V_{GS(th)}$	Gate Threshold Voltage			3.0	٧	$V_{DS} = 5V , I_{D} = 250 \mu A$
I _{GSS}	Gate-Source Leakage, Forward			100	nA	V _{GS} =20V
GSS	Gate-Source Leakage, Reverse			-100	nA	V _{GS} =-20V
	Drain-to-Source Leakage Current			2.0		V _{DS} =40V
I _{DSS}				25	μ A	V_{DS} =40 V , T_{C} =55 $^{\circ}$ C
I _{DON}	On-State Drain-Source Current	10			Α	V _{DS} =5V ,V _{GS} =10V
_	Static Drain-Source		0.065	0.13)	$V_{GS} = 10V, I_D = 3.0A$
R _{DS(on)}	On-State Resistance ②		0.084	0.2	Ω	V _{GS} =4.5V,I _D =1.5A
g_{fs}	Forward Transconductance 2		7.0		S	$V_{DS} = 15V, I_{D} = 3.0A$
$t_{d(on)}$	Turn-On Delay Time		16	20		
t _r	Rise Time		16	20	no	$V_{DD} = 25V, I_{D} = 1.0A,$
t _{d(off)}	Turn-Off Delay Time		40	70	ns $R_0=6.0\Omega$,	
t _f	Fall Time		23	50		23
Q_g	Total Gate Charge		17	25		V _25V V _10V
Q_gs	Gate-Source Charge		1.8		nC	V_{DS} =25V, V_{GS} =10V, I_{D} =2.0A ② ③
Q_{gd}	Gate-Drain ("Miller") Charge		3.9		I _D =2.UA (2	

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
I _s	Continuous Source Current (Body Diode)			2.0	А	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier
V _{SD}	Diode Forward Voltage ②	-	1	1.2	٧	T _A =25 °C ,I _S =1.5A,V _{GS} =0V
t _{rr}	Reverse Recovery Time 2		100		ns	$T_A=25$ °C, $I_F=1.5$ A, $di_F/dt=100$ A/ μ s

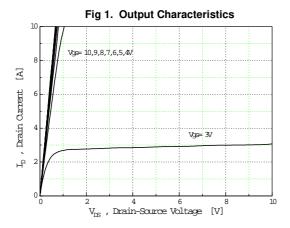
Notes;

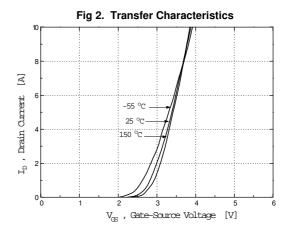
① Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

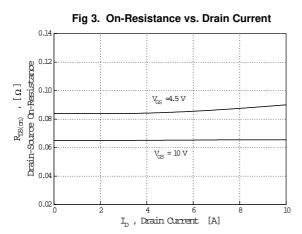
② Pulse Test : Pulse Width = 250 μ s, Duty Cycle \leq 2%

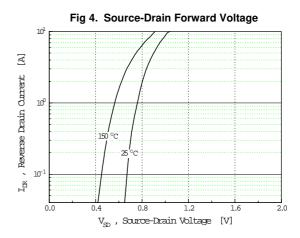
3 Essentially Independent of Operating Temperature

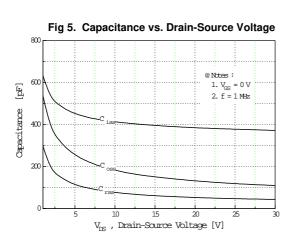


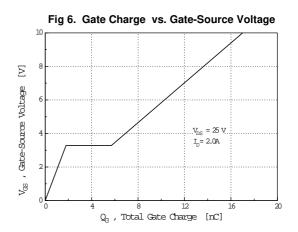




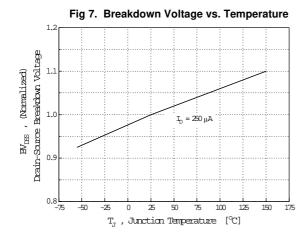












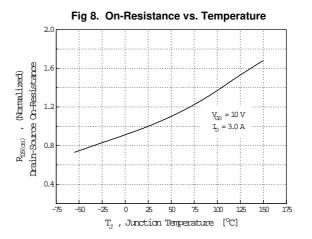
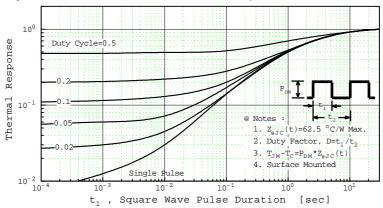


Fig 9. Nomalized Effective Transient Thermal Impedance, Junction-to-Ambient





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